

A low voltage 8-bit digital-to-analog converter using floating gate MOSFETs

Rohan Sehgal · S. S. Rajput

Received: 8 May 2007 / Revised: 22 February 2008 / Accepted: 3 April 2008 / Published online: 8 May 2008
© The Author(s) 2008

Abstract A new low voltage digital-to-analog conversion (DAC) architecture is proposed using weighted summation of voltages at the input terminals of a Floating Gate MOSFET (FGMOS). An 8-bit DAC has been designed based on this architecture and its simulation results are provided to verify its operation at ± 1.0 V. The circuit possesses good accuracy, fast dynamic performance and low power consumption. The circuit operation was verified through SPICE simulations carried out using $0.13\ \mu\text{m}$ CMOS technology.

Keywords Digital-to-analog converter (DAC) · Floating gate MOSFET · Low voltage mixed-signal circuits · Low power circuits

1 Introduction

The development of complex structures for Systems on Chip (SoC) architecture is increasingly becoming dependent on compact mixed-signal systems, embedding high performance analog blocks with complex digital circuitry on the same chip. This necessitates the design of small and simple DACs. Unfortunately, to achieve an acceptable resolution and good performance, a considerable amount of complexity and silicon area is required. Power consumption is also a dominant factor in IC design [1].

The design of DACs based on standard CMOS technologies has been pursued to overcome these constraints with some success [2–7]. Although each of the converters have some attractive features, in the form of either consuming low power [2–5], or possessing good dynamic performance [6], all of them consist of segmented or matrix architecture, rendering a complexity to the D/A converter circuit.

In this paper, a novel topology to design DACs by exploiting the ability of Floating Gate MOSFET (FGMOS) [8], a device introduced in the last decade and used frequently in digital designs, to achieve a weighted sum of input voltages is presented. Though D/A conversion through FGMOS can also be obtained using different approaches such as programming of floating gate charge [9, 10], etc., the resultant DAC is relatively complicated. The proposed circuit shows good accuracy and dynamic performance and its simple architecture and low power consumption make it quite promising for integration.

2 FGMOS transistor

An n -input FGMOS transistor consists of a gate electrode which is left electrically floating. This floating gate is capacitively coupled to an array of n control gates through a second polysilicon layer. The terminal voltages and various capacitive coupling coefficients are defined in Fig. 1(b), where V_{FG} is the floating gate potential, $V_1, V_2 \dots V_n$ are the input signal voltages and $C_1, C_2 \dots C_n$ are the capacitive coupling coefficients between the floating gate and each of the input gates.

Let Q_{FG} denote the net charge on the floating gate, which is calculated as

R. Sehgal (✉)
Netaji Subhas Institute of Technology, University of Delhi,
New Delhi 110075, India
e-mail: rohan_sehgal@yahoo.com

S. S. Rajput
ABV-Indian Institute of Information Technology &
Management, Gwalior 474010, Madhya Pradesh, India

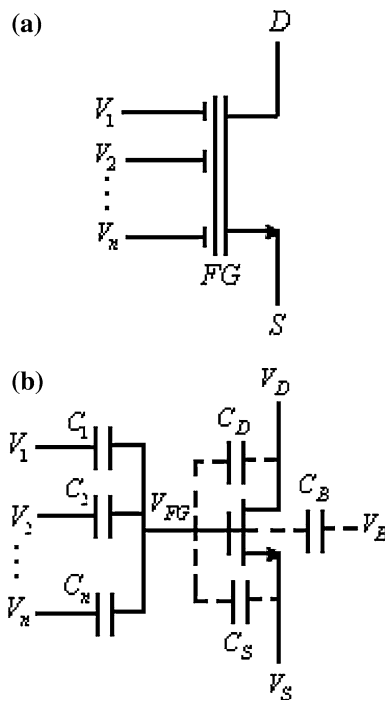


Fig. 1 FG MOST (a) Symbol (b) Equivalent circuit

$$Q_{FG} = \sum_{i=1}^n (V_i - V_{FG})C_i + (V_S - V_{FG})C_S + (V_D - V_{FG})C_D + (V_B - V_{FG})C_B \quad (1)$$

where C_S , C_D and C_B are the parasitic capacitances between gate and source, drain and body, respectively. V_S , V_D and V_B are the potentials at the respective terminals.

Under normal circumstances, Q_{FG} is equal to the initial charge on the floating gate, which is assumed to be zero in this case for simplicity. Then Eq. 1 reduces to

$$V_{FG} = \frac{\sum_{i=1}^n C_i V_i + C_S V_S + C_D V_D + C_B V_B}{\sum_{i=1}^n C_i + C_S + C_D + C_B} \quad (2)$$

Since C_S , C_D and C_B are quite small in comparison to the capacitive coefficients, C_i , Eq. 2 can be safely approximated to

$$V_{FG} \approx \sum_{i=1}^n k_i V_i \quad (3)$$

where $k_i = C_i/C_{Total}$ and

$$C_{Total} \approx \sum_{i=1}^n C_i \quad (4)$$

3 Principle of operation and design

The proposed approach for the design of the n -input DAC is explained through the circuit structure shown in Fig. 2.

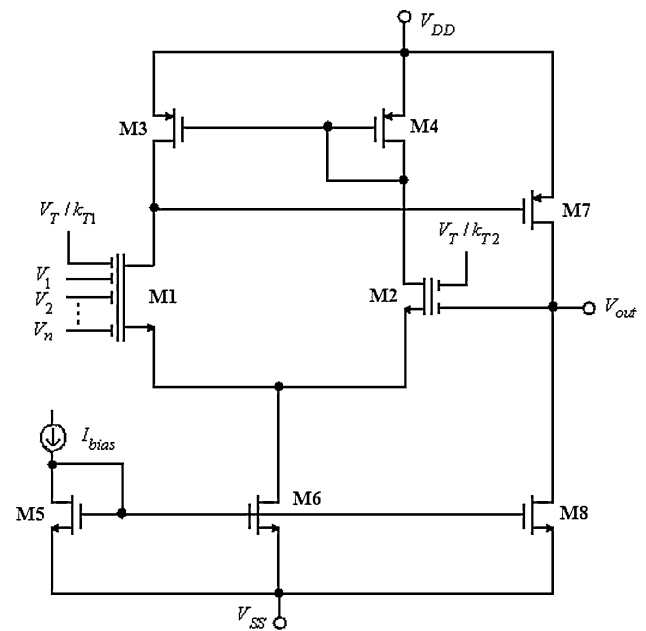


Fig. 2 Proposed n -bit DAC

Transistors M1 and M2 are multiple input floating gate MOSFETs (MIFG) with n and two gate inputs, respectively.

Now V_{FG1} , the floating gate potential of M1, can be written as

$$V_{FG1} \approx \sum_{i=1}^n k_i V_i + k_{T1} \left(\frac{V_T}{k_{T1}} \right) \quad (5)$$

where $k_{T1} = C_{T1}/C_{Total1}$, C_{T1} and C_{Total1} being the capacitive coupling coefficient of the topmost control gate of M1 and total capacitance of M1, respectively, and V_T is the threshold voltage of M1 and M2.

As M1 and M2 form a differential pair, $V_{FG1} \approx V_{FG2}$

$$V_{FG2} \approx k_o V_{out} + k_{T2} \left(\frac{V_T}{k_{T2}} \right) \approx \sum_{i=1}^n k_i V_i + k_{T1} \left(\frac{V_T}{k_{T1}} \right) \quad (6)$$

where V_{FG2} is the floating gate potential of M2, $k_{T2} = C_{T2}/C_{Total2}$ and $k_o = C_o/C_{Total2}$, C_{T2} , C_o and C_{Total2} being the capacitive coupling coefficients of the respective control gates of M2 and total capacitance of M2, respectively.

Equation 6 can be simplified as

$$V_{out} \approx \frac{1}{k_o} \sum_{i=1}^n k_i V_i \quad (7)$$

Or,

$$V_{out} \approx \frac{1}{k_o C_{Total1}} \sum_{i=1}^n C_i V_i \quad (8)$$

If the die is designed to have

$$C_i = \frac{C_{FG}}{2^i} \quad (9)$$

then Eq. 8 becomes

$$V_{out} \approx \frac{C_{FG}}{k_o C_{Total1}} \sum_{i=1}^n \frac{V_i}{2^i} \quad (10)$$

where C_{FG} is the common factor with a suitable value.

4 Low voltage D/A converter

The structure of DAC shown in Fig. 2 has been modified by using a low voltage current mirror proposed in [11], and the resultant circuit for the low voltage D/A converter (LV DAC) is shown in Fig. 3. To drive M3 in saturation, M6 is biased in sub-threshold region by selecting I_{bias1} at sufficiently low level. M6 acts as a level shifter, reducing the minimum voltage drop across the current mirror. This arrangement reduces the power supply requirements of the D/A converter, thereby reducing the power consumption.

5 Simulation results

SPICE simulations using 0.13 μm CMOS technology were carried out to validate the operation of both the DAC circuits and evaluate their performance characteristics [12]. The simulations were run at 100 M samples/s.

It may be noted that application of inputs V_T/k_{T1} and V_T/k_{T2} at the gates M1 and M2, respectively, is optional. But it was found through simulation that application of

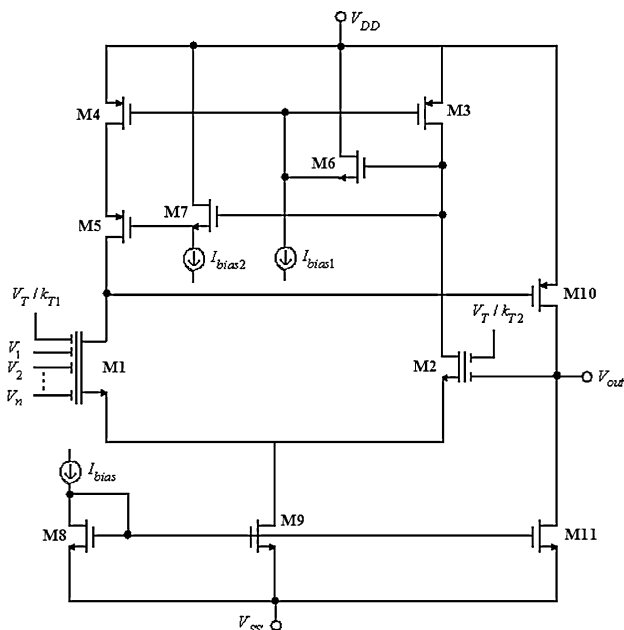


Fig. 3 Proposed n -bit low voltage DAC

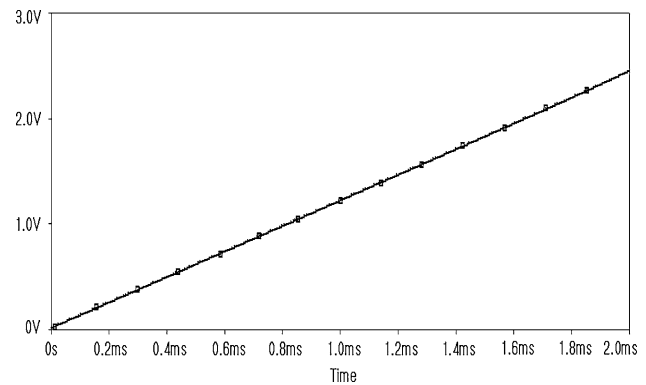


Fig. 4 DAC output voltage

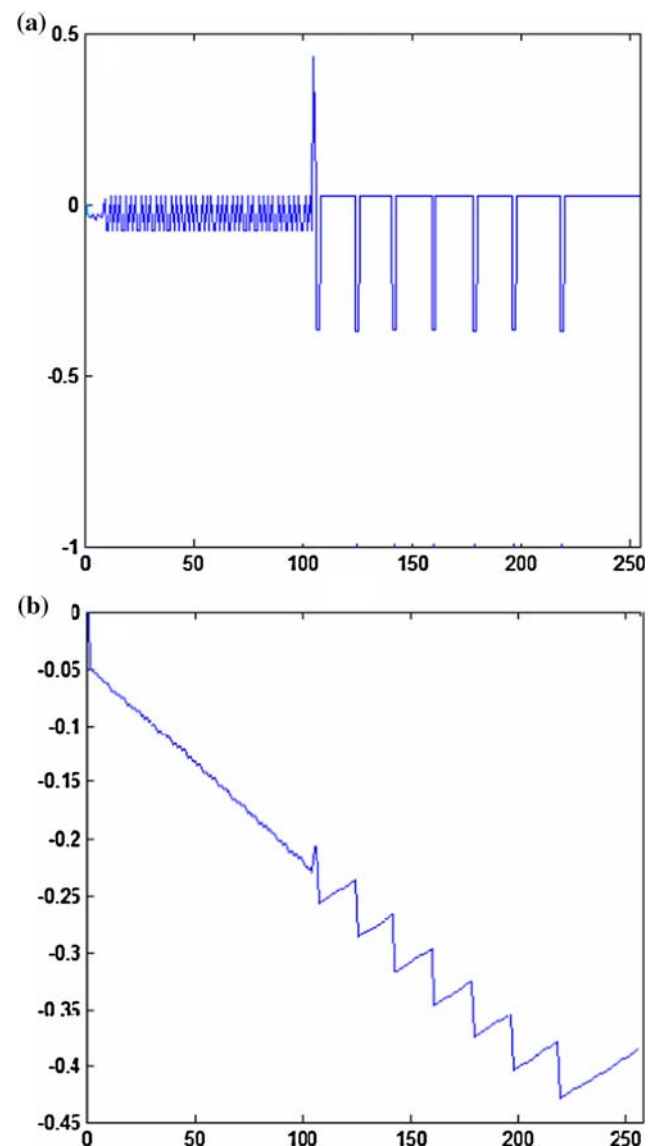


Fig. 5 Static performance of DAC (a) Differential non-linearity (b) Integrated non-linearity

Table 1 Summary of simulation results

Parameters	DAC	LV DAC
Process (μm CMOS)	0.13	0.13
Supply voltage (V)	± 2.5	± 1
Update rate (MS/s)	100	100
Resolution (bit)	8	8
Full scale range (V)	2.42	0.92
LSB (V)	0.009765625	0.00390625
DNL	0.43 LSB	0.5 LSB
INL	0.43 LSB	0.5 LSB
SFDR ($F_s = 100$ MHz) (dB)	59	58
Power dissipation (mW)	1.45	0.561

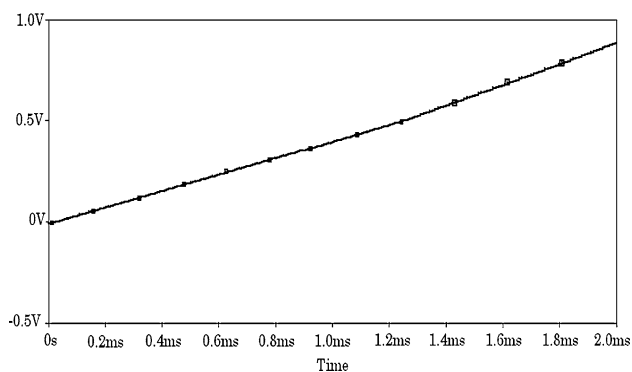
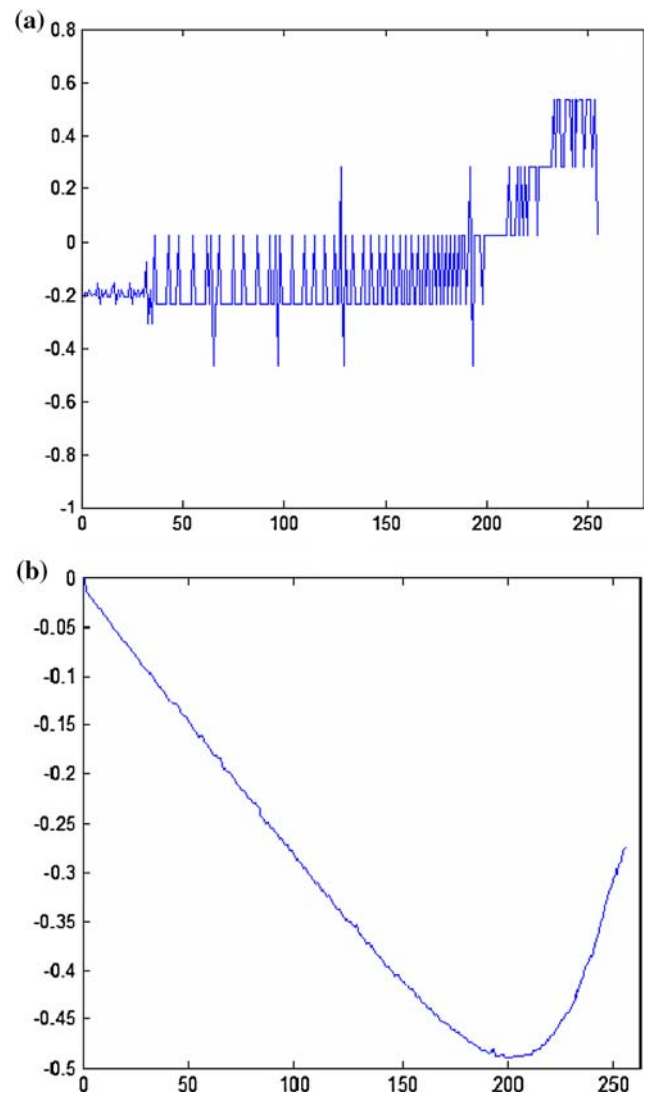
these two inputs removes the transition glitches that were found to be present in the circuit's response, thereby reducing the static non-linearities.

5.1 Proposed DAC

The circuit was operated at a power supply voltage of ± 2.5 V, whereas digital LOW and HIGH voltage levels were 0 and 1.5 V and I_{bias} was 100 μA . The output response for the 8-bit DAC is shown in Fig. 4. As seen in Fig. 5, a good accuracy is achieved, and the performance parameters INL and DNL were found to be around 0.43 LSB each. The circuit was found to possess an offset error of 25.22 mV and a full scale gain error of 0.071 V. Simulated values of other performance indices are presented in Table 1.

5.2 LV DAC

The DC output voltage and static linearities for an 8-bit LV DAC are shown in Figs. 6 and 7, respectively. The LV DAC can be operated at a power supply voltage of ± 1 V, with the digital LOW and HIGH voltage levels being 0 and 0.5 V. The bias currents, I_{bias1} , I_{bias2} and I_{bias3} , were set at 10 nA, 20 μA and 100 μA , respectively. The INL and DNL for this circuit have been found to be 0.5 LSB. A

**Fig. 6** LV DAC output voltage**Fig. 7** Static performance of LV DAC (a) Differential non-linearity (b) Integrated non-linearity

comparison of its simulated performance with the proposed DAC is provided in Table 1.

6 Conclusion

A new D/A conversion circuit architecture using floating gate MOSFETs has been presented. The scheme exploits the property of weighted summation of gate-voltages, with capacitive coupling ratios as weighting coefficients. The proposed structure possesses good accuracy and low power consumption which have been verified using SPICE simulations of 8-bit version. The power consumption and supply requirements can be further compressed by employing a low voltage current mirror, without much effect on the performance. Due to their simple structures, the proposed DACs are suitable for complex on-chip mixed-signal circuit blocks.

Open Access This article is distributed under the terms of the Creative Commons Attribution Noncommercial License which permits any noncommercial use, distribution, and reproduction in any medium, provided the original author(s) and source are credited.

References

1. Allen, P., & Holberg, D. (2002). *CMOS analog circuit design*. New York: Oxford University Press.
2. Wong, L., Kwok, C., & Rigby, G. (1999). A 1-V CMOS D/A converter with multi-input floating-gate MOSFET. *IEEE Journal of Solid-State Circuits*, 34(10), 1386–1390.
3. Greenley, B., Veith, R., Chang, D., & Moon, U. (2005). A low-voltage 10-bit CMOS DAC in 0.01 mm² die area. *IEEE Transactions on Circuits and Systems-II: Express Briefs*, 52(5), 246–250.
4. Rantala, A., Kuivalainen, P., & Aberg, M. (1999). An 8-bit and a 10-bit low power high-speed neuron MOS digital-to-analog converter in 0.04 mm². *European Solid-State Circuits Conference/IEEE*, pp. 310–313.
5. Wang, H., Kao, H., & Lee, T. (2004). An 8-bit 2-V 2-mW 0.25-mm² CMOS DAC. *Asia-Pacific Conference on Advanced System Integrated Circuits/IEEE*, pp. 102–105.
6. Bugeja, A. R., Song, B., Rakers, P. L., & Gillig, S. F. (1999). A 14-b 100 M sample/s CMOS DAC designed for spectral performance. *IEEE International Solid-State Circuits Conference*, pp. 148–149.
7. Van De Plassche R. (1994). *Integrated analog-to-digital and digital-to-analog converters*. New York: Kluwer Academic Publishers.
8. Shibata, T., & Ohmi, T. (1992). A functional MOS transistor featuring gate-level weighted sum and threshold operation. *IEEE Transactions on Electron Devices*, 39(6), 1444–1455.
9. Serrano, G., & Hasler, P. (2004). A floating-gate DAC array. *IEEE International Symposium on Circuits and Systems*, pp. 357–360.
10. Lopez-Martin, A. J., Carlosena, A., & Ramirez-Angulo, J. (1999). D/A conversion based on multiple-input floating-gate MOST. *Midwest Symposium on Circuits and Systems/IEEE*, pp. 149–152.
11. Rajput, S. S., & Jamuar, S. S. (2003). A current mirror for low voltage, high performance analog circuits. *Analog Integrated Circuits and Signal Processing*, 36, 221–233.
12. Hendriks, P. (1997). Specifying communication DAC's. *IEEE Spectrum*, pp. 58–69.



S. S. Rajput was born on July 1, 1957, at village Bashir Pur, District Bijnor UP, India. He received his B.E. in Electronics and Communication Engineering and M.E. in Solid State Electronics Engineering from University of Roorkee, Roorkee, India (now IIT, Roorkee) in 1978 and 1981, respectively, and was awarded University gold medal in 1981. He earned his Ph.D. degree from Indian

Institute of Technology, Delhi in 2002 and his topic of research was “Low voltage current mode analog circuit structures and their applications”. He joined National Physical Laboratory, New Delhi, India as Scientist B in 1983 and was Scientist F when he moved to ABV-IIITM Gwalior as Professor. He has worked for the design, development, testing and fabrication of an instrument meant for space exploration under the ISRO-NPL joint program for development of scientific instruments for the Indian Satellite SROSS-C and SROSS-C2 missions. His research interests include low voltage analog VLSI, instrument design for space applications, digital signal processing, fault tolerant design, and fault detection. He has chaired many sessions in Indian as well as International conferences. He is fellow member of IETE (India). He was awarded the Best Paper Award for IETE Journal of Education for the year 2002. He has delivered many invited talks on low voltage analog VLSI. Several tutorials have been presented in International Conferences on his research work. He has more than 60 publications in national and international journals and conferences including a book chapter. He is presently the associate editor of International Journal of Electronics, UK and editorial board member of Journal of Active and Passive Electronic Devices, USA Journal of Programmable Devices, Circuits, and Systems (PDCS), Egypt.



Rohan Sehgal was born on March 10, 1986 in Delhi, India. He received his B.E. in Electronics and Communication Engineering from Netaji Subhas Institute of Technology, University of Delhi in 2007 and was awarded the Institute Medal for Best B.E. Thesis. He worked as a research intern at Delft University of Technology, The Netherlands, on Ultra Low Power Sense Amplifier Cardiac Signal Analysis in 2007. His research interests include low

voltage low power analog and mixed-signal design, neuromorphic engineering and biomedical VLSI.